



First International Workshop on Automotive Reliability & Test in Europe ARTe Workshop

Virtual conference
February 5, 2021

<http://arte.ttc-events.org/>

General Chairs

Y. Zorian – Synopsys (US)
P. Bernardi – PoliTo (IT)

Program Chairs

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Program committee (not limited to)

D. Appello – STMicroelectronics
O. Ballan – Ethernovia
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G. Boschi – Intel
A. Bosio – Lyon Inst. of Nanotech.
A. Cron – Synopsys
P. Engelke – Infineon Technologies
C. Eychenne – Bosch
A. Hales – Texas Instruments
L. Harrison – Mentor
P. Harrod – ARM
G. Harutyunyan – Synopsys
A. Majumdar – Xilinx
N. Maor – Qualcomm
R. Mariani – NVIDIA
T. McLaurin – ARM
R. Montino – Elmos Semiconductor
N. Mukherjee – Mentor
R. Parekhji – Texas Instruments
S. Patil – Qualcomm
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P. Rech – Politecnico di Torino
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F. Venini – Xilinx
H. M. von Staudt – Dialog Semicond.
M. Wahl – Universität Siegen
J. Yi – AMD

Call for Submissions

Automotive electronics is becoming more and more relevant in the daily life, especially with the advent of the autonomous driving. People will become 100% dependent on the proper operation of the electronic systems. The Automotive Reliability and Test workshop in Europe (ARTe or ART in Europe) intends to focus exclusively on test and reliability of automotive electronics, including IC design, test development, system-level integration, production testing, in-field test, diagnosis and repair solutions, as well as architectures and methods for reliable and safe operation in the field.

Given the success of the first five editions in the US, we would like to celebrate the ART anniversary with an extraordinary edition to be held in Europe. The ARTe Workshop wants to offer a forum for industry specialists and academic researchers to present and discuss these challenges and emerging solutions. For this first edition in the frame of the **DATE conference**, special focus will be given on Design-for-Test solutions.

Topic Areas – You are invited to participate and submit your contributions to the ARTe Workshop. The workshop's areas of interest include (but are not limited to) the following topics:

- *Automotive Design-for-Test: enable high quality at low cost*
- *Statistical post-processing, Machine Learning, and AI for test and reliability*
- *Latent defect activation during production testing*
- *Built-In Self-Test in automotive systems: digital, analog, mixed-signal*
- *Reuse of test infrastructure and New Product Development acceleration*
- *Dependability challenges of autonomous driving and e-mobility*
- *Functional safety and cyber-security*
- *Automotive standards and certification - ISO 26262, AEC-Q100*
- *Approximate computing for automotive*
- *Verification and validation of automotive systems*
- *Fault tolerance and self-checking circuits*
- *Aging effects on automotive electronics*
- *Power-up, power-down and periodic test*
- *System level test*
- *Functional and structural test generation*
- *Automotive production testing*

Submission Instructions – The Workshop asks for the submission of **Extended Abstracts of two pages**; final submission version can be extended. **Submission website is open**. Detailed submission instructions can be found at the Workshop's website: <http://arte.ttc-events.org/>. All submissions will be evaluated for selection with respect to their suitability for the workshop, originality, technical soundness, and presented results. Selected submissions can be accepted for regular or short presentation at the Workshop.

Publications – The workshop will make available to all participants an Electronic Workshop Digest, which includes the material that authors are willing to provide (papers, presentations, videos, etc.).

Key Dates

- Submission deadline (**extended**): ~~December 13, 2020~~ **December 23, 2020**
- Notification of acceptance: ~~January 8, 2021~~ **January 11, 2021**
- Final presentation material: ~~January 24, 2021~~ **January 27, 2020**

Further Information

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